

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/055,944	MIWA ET AL.
	<b>Examiner</b> Brian Szmal	<b>Art Unit</b> 3736

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
As Above		5-906	BB